



GRFN200F1200A

GL Silicon Fast Recovery Epitaxial Diode

General Description:

FRED from GL utilizes advanced processing techniques to achieve ultrafast recovery times and higher forward current. Its soft recovery characteristics and high reliability suit for wide industrial applications.

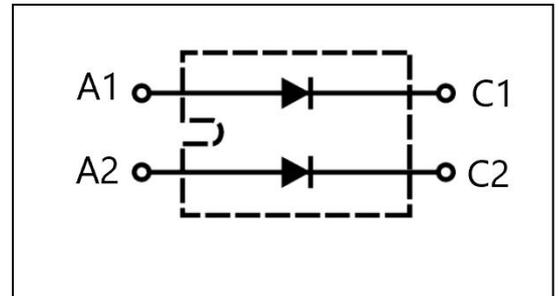
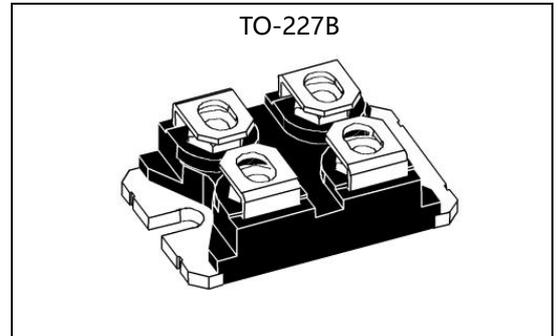
| | | |
|-----------------------------|-------|----|
| V_{RRM} | 1200 | V |
| I_{FAVM} | 2×100 | A |
| $P_D(T_C=25^\circ\text{C})$ | 250 | W |
| t_{rr} | 40 | nS |

Features:

- Ultrafast Recovery Time
- Soft Recovery Characteristics
- Low Recovery Loss
- Low Forward Voltage
- High Surge Current Capability
- Low Leakage Current

Applications:

- Freewheeling, Snubber, Clamp
- Inversion Welder
- PFC
- Plating Power Supply
- Ultrasonic Cleaner and Welder
- Converter & Chopper
- UPS



Absolute (T_c=25°C unless otherwise specified) :

| Symbol | Parameter | Test conditions | Rating | Units |
|-----------------|--------------------------------------|---|-------------|--------|
| V_R | Maximum D.C. Reverse Voltage | | 1200 | V |
| V_{RRM} | Maximum Repetitive Reverse Voltage | | 1200 | V |
| $I_{F(AV)}$ | Average Forward Current | $T_C=110^\circ\text{C}$, Per Diode | 100 | A |
| | | $T_C=110^\circ\text{C}$, Per Package | 182 | A |
| $I_{F(RMS)}$ | RMS Forward Current | $T_C=110^\circ\text{C}$, Per Diode | 150 | A |
| I_{FSM} | Non-Repetitive Surge Forward Current | $T_J=45^\circ\text{C}$, $t=10\text{ms}$, 50Hz, Sine | 900 | A |
| P_D | Power Dissipation | | 250 | W |
| T_J | Junction Temperature | | -40 to +150 | °C |
| T_{STG} | Storage Temperature Range | | -40 to +150 | °C |
| Torque | Module-to-Sink | Recommended (M4) | 1.5 | Nm |
| $R_{\theta JC}$ | Thermal Resistance | Junction-to-Case | 0.5 | °C / W |



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Electrical Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified) :

| Symbol | Parameter | Test Conditions | Rating | | | Units |
|-----------|-------------------------------|---|--------|------|------|-------|
| | | | Min. | Typ. | Max. | |
| I_{RM} | Reverse Leakage Current | $V_R = 1200V$ | -- | -- | 3 | mA |
| | | $V_R = 960V, T_J = 125^\circ\text{C}$ | -- | -- | 15 | mA |
| V_F | Forward Voltage | $I_F = 100A$ | -- | -- | 2.2 | V |
| | | $I_F = 200A$ | -- | -- | 2.5 | V |
| | | $I_F = 100A, T_J = 150^\circ\text{C}$ | -- | -- | 1.8 | V |
| | | $I_F = 200A, T_J = 150^\circ\text{C}$ | -- | -- | 2.3 | V |
| t_{rr} | Reverse Recovery Time | $I_F = 1A, V_R = 30V, di_F/dt = -400A/\mu s$ | -- | 40 | -- | ns |
| t_{rr} | Reverse Recovery Time | $I_F = 100A, V_R = 600V,$ $di_F/dt = -600A/\mu s$ | -- | 150 | -- | ns |
| | | $I_F = 100A, V_R = 600V,$ $di_F/dt = -600A/\mu s, T_J = 125^\circ\text{C}$ | -- | 255 | -- | ns |
| I_{RRM} | Max. Reverse Recovery Current | $I_F = 100A, V_R = 600V,$ $di_F/dt = -600A/\mu s$ | -- | 38 | -- | A |
| | | $I_F = 100A, V_R = 600V,$ $di_F/dt = -600A/\mu s, T_J = 125^\circ\text{C}$ | -- | 52 | -- | A |



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Characteristics Curve:

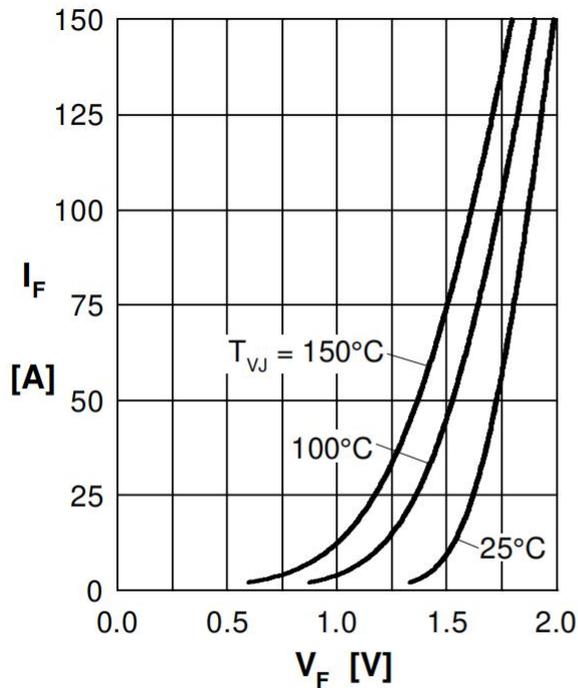


Fig. 1 Forward current I_F versus V_F

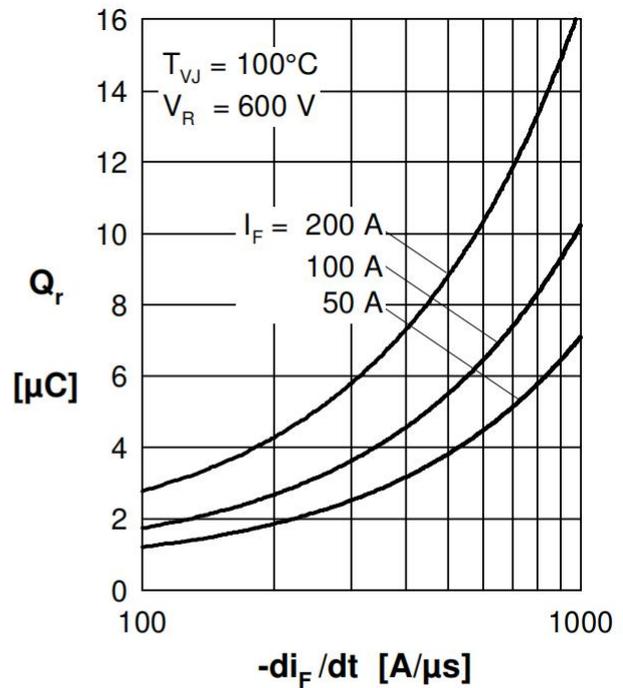


Fig. 2 Typ. reverse recov. charge Q_{rr} versus $-di_F/dt$

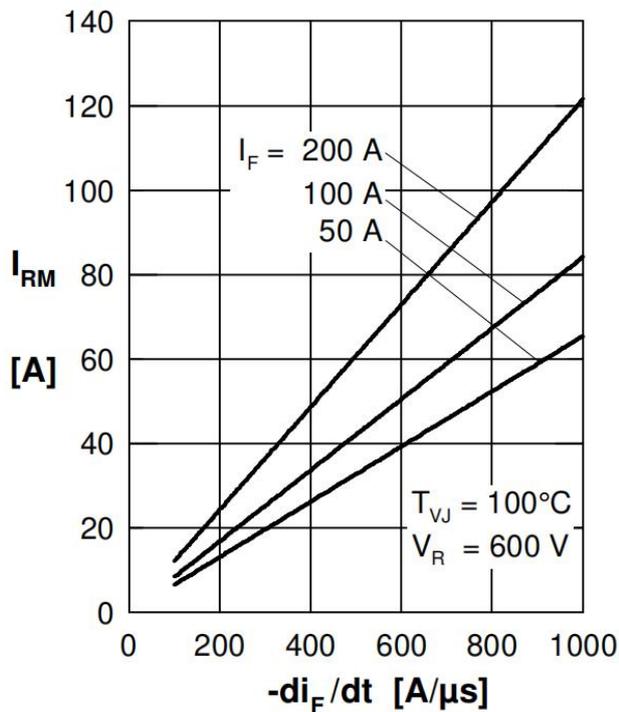


Fig. 3 Typ. peak reverse current I_{rr} versus $-di_F/dt$

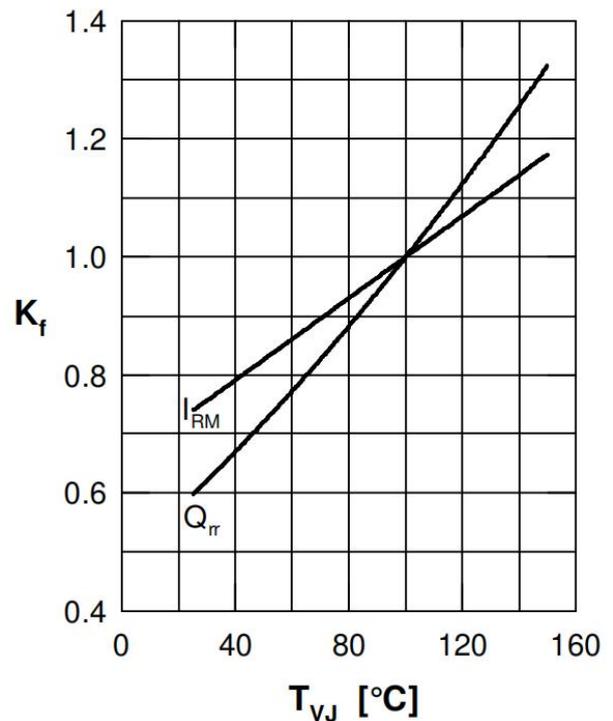


Fig. 4 Dyn. parameters Q_r, I_{RM} versus T_{VJ}



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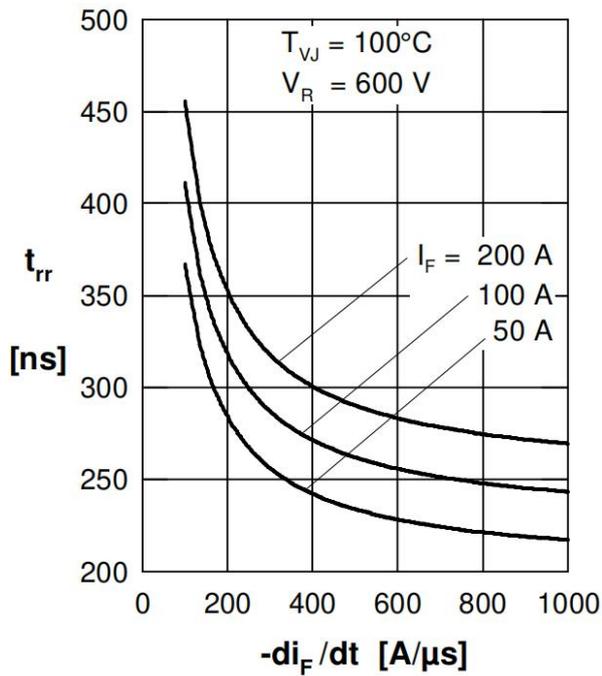


Fig. 5 Typ. recovery time t_{rr} versus $-di_F/dt$

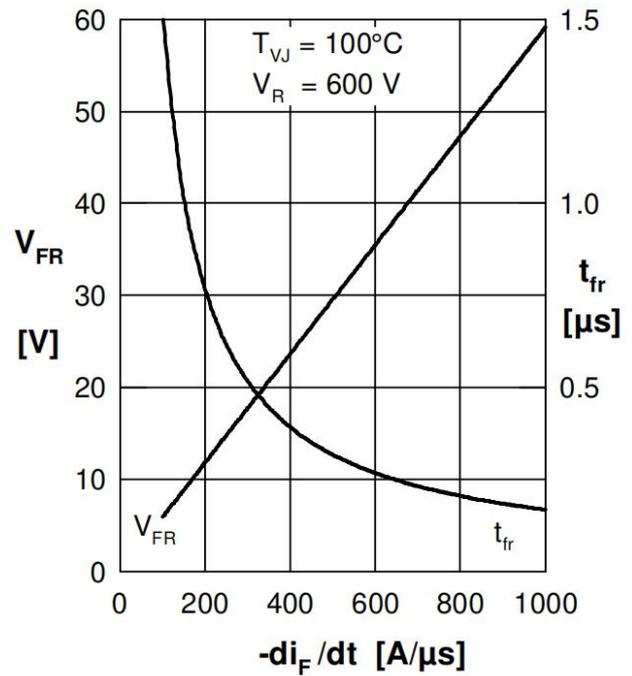


Fig. 6 Typ. peak forward voltage V_{FR} and t_{fr} versus di_F/dt

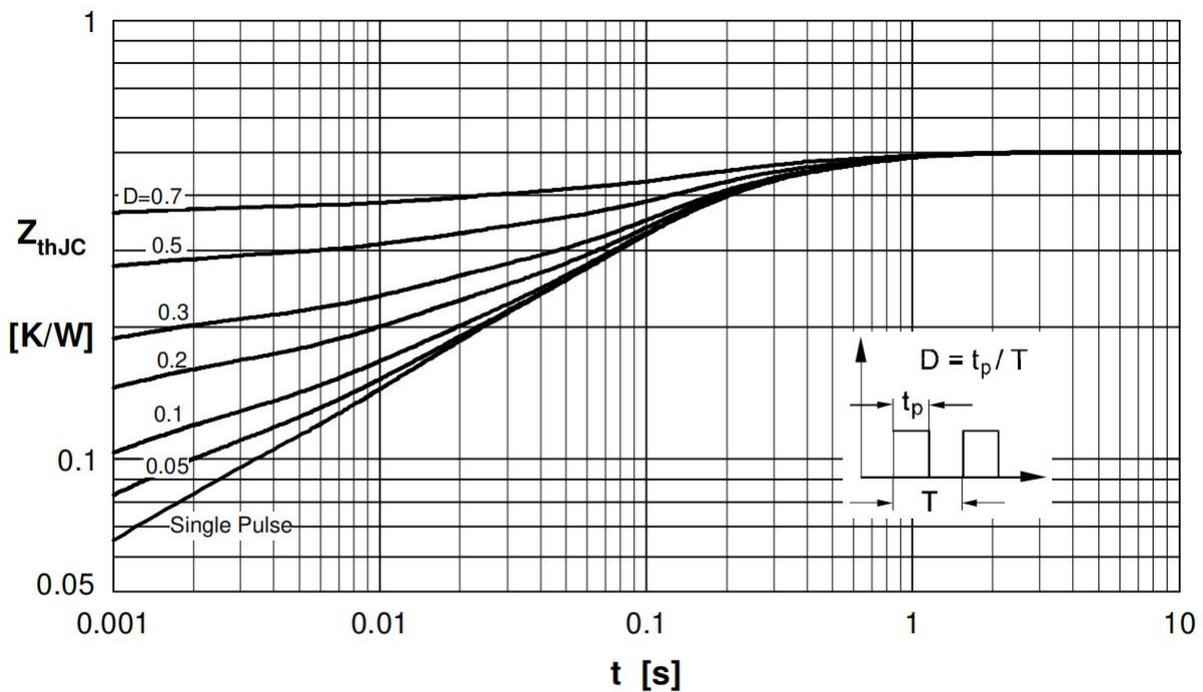


Fig. 7 Transient thermal impedance junction to case